

Transaction Information

Tool ID	ETS436
Tool Status	Disconnected
Location	Dresden, Germany
Wafer Size	300 mm
Fab Section	Test
Tool Available Date	2021-10-04

General Product Information

Vendor Supplier	CREDESCENCE
Model	SAPPHIRE
Vintage	2007
Serial No	70401
Asset Description	Wafer Tester
Software Version	LTX Credence customized for AMD/ Globalfoundries
CIM	n/a
Process	Wafer Test

Hardware Configuration (Fab)

System Type	Description	Quantity	Status
Main System	Tester	1	
Handler System	NONE	0	OK
Factory Interface	NONE	0	OK
Options System	Adapter for TEL P12XIn+	1	OK
Others	n/a	0	

Hardware Configuration (Subfab / Auxilliary Units)

Description	Quantity	Status
cold idled LTX CREDESCENCE Sapphire Tester	1	

Missing/Faulty Parts / Accesories List

Description	Quantity
channel boards and DPS units defect	5

Tool Pictures

General

Tool Reference









Manufacture Serial

S/N Tool Plate



Additional Configuration Files